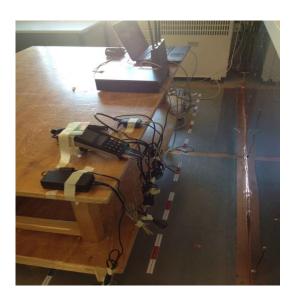


CONDUCTED AND RADIATED MEASUREMENT PHOTO

FCCID: XKB-D5000CLWIBT

1.1 Conducted emission







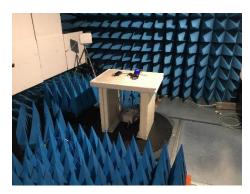
1.2 Radiated emissions







Test setup on OATS



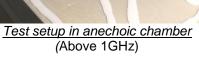




<u>Test setup in anechoic chamber</u> (Below 1GHz)





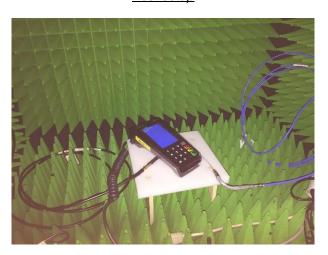






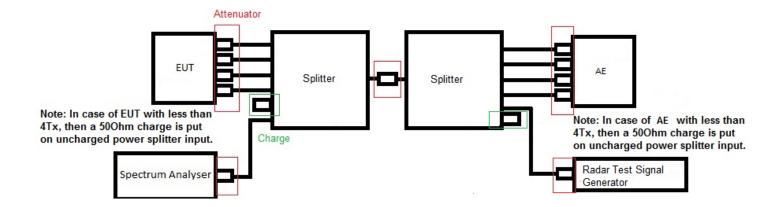


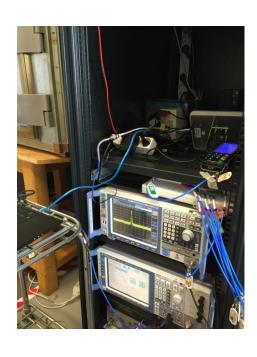
Test setup





1.3 DFS setup





Photograph for DFS Detection Thresholds Determination, Reference Noise Level, Channel Loading

1.4